

<b>Notice of References Cited</b>	Application/Control No. 10/633,595		Applicant(s)/Patent Under Reexamination OIKAWA ET AL.	
	Examiner Patrick J. Lee		Art Unit 2878	Page 1 of 1

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*	A	US-5,528,027	06-1996	Mizutani, Hideo	250/234
*	B	US-5,760,390	06-1998	Vezzalini et al.	250/221
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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